

ci230 - High Speed NFC Test System



- High speed
- Arbitrary signal generator
- Real-time scope
- Power amplifier
- Easy to use
- Integrated VNA



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world's first fully integrated NFC Test System
in a revolutionary form factor

General Description

The ci230 high speed tester takes a whole new approach to NFC testing that makes it faster and easier to conduct pre-certification testing, makes the certification process quicker and cheaper, lets customers get a fast return on investment — and a competitive advantage from speeding up time to market.



Benefits

- Time and cost saving
- Reduce setup time and costs
- All in one test and debug system
- Fast report generation
- Simple automation API
- Easy customer test bench integration

Supported Standards

- NFC Forum CR15 / TR15.0
- EMV PCD 3.2a / PICC 3.2b
- ISO 10373-6 / ISO 10373-7
- ISO 24192
- ISO 14443 proximity A / B
- ISO 15693 vicinity
- BSI TR-03105:2016 Part 2 / Part 4

Key Features

- Ultra fast testing
- Integrated RF power amplifier
- Advanced Shmoo analysis
- Flexible API (RCI)
- Absolute PCD / PICC sensitivity measurement
- Integrated VNA
- PCD & PICC emulator



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